

Notice of References Cited	Application/Control No. 10/643,966	Applicant(s)/Patent Under Reexamination ISHIGURO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0063583	04-2003	PADOVANI et al.	370/329
	B	US-6,141,388	10-2000	Servais et al.	375/262
	C	US-2002/0193135	12-2002	Nakano, Takayuki	455/524
	D	US-2002/0045449	04-2002	Oobayashi, Mamiko	455/436
	E	US-2003/0152031	08-2003	Toskala et al.	370/236
	F	US-2005/0039101	02-2005	Torsner, Johan	714/748
	G	US-2004/0146033	07-2004	Soderstrom et al.	370/338
	H	US-2004/0081248	04-2004	Parolari, Sergio	375/259
	I	US-2003/0224774	12-2003	Cheng et al.	455/422.1
	J	US-2002/0150094	10-2002	Cheng et al.	370/389
	K	US-2002/0136192	09-2002	Holma et al.	370/347
	L	US-2002/0080719	06-2002	Parkvall et al.	370/235
	M	US-2003/0131299	07-2003	Ahn et al.	714/748

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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